

Application/Control No.	Applicant(s)/Patent under Reexamination
10/656,158	PARK ET AL.
Examiner	Art Unit
Hong Cho	2616

	SEARCHED						
Class	Subclass	Date	Examiner				
370	229-232, 252-254, 328	3/28/2007	нс				
	389, 392,	l					
	400, 401						
	466	· ·					
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INI	ERFERENC	ERENCE SEARCHED		
Class	Subclass	Date	Examiner	
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		SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR					
370/229-232, 252-254, 328, 389, 392, 400, 401, 466 (text search - see search history printout)	4/2/2007	нс					
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